

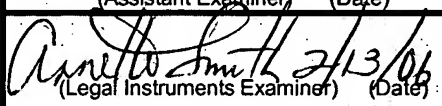


<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/805,048	LIN, JYH CHAIN	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
327	108			327	151	165			
INTERNATIONAL CLASSIFICATION									
H03K	3100								
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HIEP NGUYEN 02.09.06 (Assistant Examiner) (Date)				 TUAN T. LAM PRIMARY EXAMINER (Primary Examiner)				Total Claims Allowed: 7	
 (Legal Instruments Examiner) (Date)				2/11/06 (Date)				O.G. Print Claim(s) 1	O.G. Print Fig. 3

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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